


<b>Search Notes</b> 	<b>Application/Control No.</b> 10541906	<b>Applicant(s)/Patent Under Reexamination</b> FINCH ET AL.
	<b>Examiner</b> Barker, Matthew	<b>Art Unit</b> 3662

### SEARCHED

Class	Subclass	Date	Examiner
342	157.2, 194,	12/21/2006	Hien Le
342	163, 159-164	8/9/2007	Hien Ly
342	160	6/12/2008	MMB
	updated	1/2/2009	MMB
	updated	8/21/2009	MMB

### SEARCH NOTES

Search Notes	Date	Examiner
Inventor's name search	12/20/2006	Hien Ly
NPL search	12/20/2006	Hien Ly
Plus search	12/20/2006	Hien Ly
Text search	12/20/2006	Hien ly
NPL search (update)	8/8/2007	Hien ly
Text search (update)	8/8/2007	Hien Ly
342/104, 105, 109, 115, 194, 195, 161, 162, 164 - test search, see printoutx	6/12/2008	MMB
EAST text search - see printout	6/13/2008	MMB
Updated text search - see printout	1/2/2009	MMB
Updated text search - see printout	8/21/2009	MMB

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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